## BEST AVAILABLE COPY

## INTERNATIONAL SEARCH REPORT

International Application No
/IL2004/000613

A. CLASSI	FICATION OF SUBJECT MATTER G12B21/02 G01N21/65		
110 /	GALDER/ OF GOATTER/ OO		
According to	o International Patent Classification (IPC) or to both national classifica	ation and IPC	
B. FIELDS	SEARCHED		
Minimum do	ocumentation searched (classification system followed by classification $6128 - 601N - 601J$	on symbols)	
1,0 ,	dies doin dois		
Documental	tion searched other than minimum documentation to the extent that s	uch documents are included in the fields se	arched
Electronic d	ata base consulted during the international search (name of data base	se and, where practical, search terms used)	
EPO-In	ternal, WPI Data, PAJ, INSPEC, COMPE	NDEX, EMBASE	
	ENTS CONSIDERED TO BE RELEVANT	numi nacranac	Relevant to claim No.
Category *	Citation of document, with indication, where appropriate, of the rek	availi hassañes	Tipotan to day 1110.
х	SHUBEITA G T ET AL: "Scanning ne		1-14,
	optical microscopy using semicond		16-22, 29-33
	nanocrystals as a local fluoresce fluorescence resonance energy tra		£3-33
	source"		ı
	JOURNAL OF MICROSCOPY BLACKWELL S	OCIENCE	·
	vol. 210, no. 3, June 2003 (2003-	-06),	
	pages 274-278, XP002300714   ISSN: 0022-2720		
	cited in the application		
	figure 2 paragraph 'EXPERIMENTAL!		
Υ	par agraph Extentionation		15,38
А		·	23-28, 34-37
	<del></del>		04 07
	-	-/	
			•
X Funt	t her documents are listed in the continuation of box C.	Fatent family members are listed in	1 аплех.
° Special ca	ategories of cited documents :	"T later document published after the inter or priority date and not in conflict with	mational filing date
"A" docume	ent defining the general state of the art which is not dered to be of particular relevance	or phonty date and not in contact with cited to understand the principle or the invention	ory underlying the
*E* earlier of filling of	document but published on or after the international date	"X" document of particular relevance; the connot be considered novel or cannot	be considered to
which	ant which may throw doubts on priority claim(s) or is ched to establish the publication date of another	involve an inventive step when the doc "Y" document of particular relevance; the c	cument is taken alone almed invention
O docum	n or other special reason (as specified) ent reterring to an oral disclosure, use, exhibition or	cannol be considered to involve an im- document is combined with one or mo- ments, such combination being obvious	re other such docu-
'P' docume	means ent published prior to the international filing date but han the priority dale claimed	in the art.  *&* document member of the same patent t	
	actual completion of the international search	Date of mailing of the international sear	
2	4 October 2004	25/10/2004	
Name and	mailing address of the ISA	Authorized officer	
	European Patent Ciffice, P.B. 5818 Patentlaan 2 NL - 2280 NV PRISWIK The Cast TN 240, 2000 Tx 31 551 and N		
1	Tel (+31-70) 340-2040, Tx. 31 651 epo ni, Fax: (+31-70) 340-3016	Polesello, P	

Form PCT/ISA/210 (second sheet) (January 2004)

## BEST AVAILABLE COPY

## INTERNATIONAL SEARCH REPORT

International Application No
i 'IL2004/000613

	PARTY DOCUMENTS CONCREDED TO BE DELEVANT	
Category °	ation) DOCUMENTS CONSIDERED TO BE RELEVANT  Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
Y	VICKERY S A ET AL: "Combining AFM and FRET for high resolution fluorescence microscopy"	15,38
	JOURNAL OF MICROSCOPY 2001 UNITED KINGDOM, vol. 202, no. 2, May 2001 (2001-05), pages 408-412, XP002300713 ISSN: 0022-2720	·
	figure 2 paragraph 'EXPERIMENTAL!	
A		1-14, 16-37
X	OKAMOTO T ET AL: "NEAR-FIELD SCANNING OPTICAL MICROSCOPE USING A GOLD PARTICLE" JAPANESE JOURNAL OF APPLIED PHYSICS, PUBLICATION OFFICE JAPANESE JOURNAL OF APPLIED PHYSICS. TOKYO, JP, vol. 36, no. 2A,	1-13, 16-20, 22-27, 33-37
	1 February 1997 (1997-02-01), pages L166-L169, XP000732147 ISSN: 0021-4922	
<b>A</b> .	the whole document	14,15, 21, 28-32,38
X	ANDERSON MARK S: "Locally enhanced Raman spectroscopy with an atomic force microscope" APPLIED PHYSICS LETTERS, AMERICAN INSTITUTE OF PHYSICS. NEW YORK, US, vol. 76, no. 21, 22 May 2000 (2000-05-22), pages 3130-3132, XP012025398 ISSN: 0003-6951 cited in the application	1-12, 16-23, 25-27, 32-34, 36,37
<b>A</b> .	the whole document	13-15, 24, 28-31, 35-38
х	WESSEL J: "Surface-enhanced optical microscopy" JOURNAL OF THE OPTICAL SOCIETY OF AMERICA B (OPTICAL PHYSICS) USA, vol. 2, no. 9, September 1985 (1985-09), pages 1538-1541, XP002300715 ISSN: 0740-3224	1-12, 16-20, 23,25, 34,36
A	figures 1,2 paragraphs 'INTRODUCTION!, 'SIGNAL!	13-15, 21,22, 24, 26-33, 35,37,38